


<b>Search Notes</b> 	<b>Application/Control No.</b> 10551645	<b>Applicant(s)/Patent Under Reexamination</b> OTSUKA ET AL.
	<b>Examiner</b> Hai H Huynh	<b>Art Unit</b> 3741

SEARCHED			
Class	Subclass	Date	Examiner
123	193.6	3-20-07	AW
123	193.4	3-20-07	AW
update	search	1-2-08	HHH
123	41.34	1-2-08	HHH
123	41.35	1-2-08	HHH
29	888.04	1-2-08	HHH
		10-21-08	HHH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	3-20-07	AW
	1-2-08	HHH
	10-21-08	HHH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
above	search	10-21-08	HHH

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